

Small, Low Power, 2-Axis ±3 g iMEMS® Accelerometer

ADXL323

FEATURES

2-axis sensing Small, low-profile package 4 mm × 4 mm × 1.45 mm LFCSP_LQ Low power 180 μA at V₅ = 1.8 V (typical) Single-supply operation 1.8 V to 5.25 V 10,000 g shock survival Excellent temperature stability BW adjustment with a single capacitor per axis RoHS/WEEE lead-free compliant

APPLICATIONS

Cost-sensitive, low power, motion- and tilt-sensing applications

- Mobile devices
- Gaming systems
- Disk drive protection
- Image stabilization
- Sports and health devices

GENERAL DESCRIPTION

The ADXL323 is a small, thin, low power, complete 2-axis accelerometer with signal-conditioned voltage outputs, all on a single, monolithic IC. The product measures acceleration with a minimum full-scale range of ± 3 g. It can measure the static acceleration of gravity in tilt-sensing applications, as well as dynamic acceleration resulting from motion, shock, or vibration.

The user selects the bandwidth of the accelerometer using the C_X and C_Y capacitors at the X_{OUT} and Y_{OUT} pins. Bandwidths can be selected to suit the application, with a range of 0.5 Hz to 1600 Hz.

The ADXL323 is available in a small, low profile, 4 mm \times 4 mm \times 1.45 mm, 16-lead, plastic lead frame chip scale package (LFCSP_LQ).

FUNCTIONAL BLOCK DIAGRAM

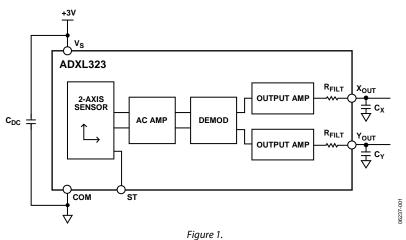


TABLE OF CONTENTS

Features 1
Applications1
General Description 1
Functional Block Diagram 1
Revision History
Specifications
Absolute Maximum Ratings 4
ESD Caution
Pin Configuration and Function Descriptions
Typical Performance Characteristics
Theory of Operation11
Mechanical Sensor11

Performance	. 11
Applications	. 12
Power Supply Decoupling	. 12
Setting the Bandwidth Using Cx, Cy, and Cz	. 12
Self Test	. 12
Design Trade-Offs for Selecting Filter Characteristics: The Noise/BW Trade-Off	
Use with Operating Voltages Other Than 3 V	. 12
Axes of Acceleration Sensitivity	. 13
Outline Dimensions	. 14
Ordering Guide	. 14

REVISION HISTORY

8/06—Revision 0: Initial Version	
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SPECIFICATIONS

 $T_A = 25^{\circ}C$, $V_S = 3 V$, $C_X = C_Y = 0.1 \mu$ F, acceleration = 0 g, unless otherwise noted. All minimum and maximum specifications are guaranteed. Typical specifications are not guaranteed.

Parameter	Conditions	Min	Тур	Max	Unit
SENSOR INPUT	Each axis				
Measurement Range		±3	±3.6		g
Nonlinearity	% of full scale		±0.3		%
Package Alignment Error			±1		Degrees
Inter-Axis Alignment Error			±0.1		Degrees
Cross Axis Sensitivity ¹			±1		%
SENSITIVITY (RATIOMETRIC) ²	Each axis				
Sensitivity at X _{OUT} , Y _{OUT}	$V_s = 3 V$	270	300	330	mV <i>/g</i>
Sensitivity Change Due to Temperature ³	$V_s = 3 V$		±0.015		%/°C
ZERO g BIAS LEVEL (RATIOMETRIC)	Each axis				
0 g Voltage at Хоит, Youт	$V_s = 3 V$	1.35	1.5	1.65	V
0 g Offset vs. Temperature			±0.6		m <i>g</i> /°C
NOISE PERFORMANCE					
Noise Density Xout, Yout			280		µg/√Hz rms
FREQUENCY RESPONSE ⁴					
Bandwidth Xout, Yout ⁵	No external filter		1600		Hz
R _{FILT} Tolerance			32 ± 15%		kΩ
Sensor Resonant Frequency			5.5		kHz
SELF TEST ⁶					
Logic Input Low			+0.6		V
Logic Input High			+2.4		V
ST Actuation Current			+60		μΑ
Output Change at Xout	Self Test 0 to Self Test 1		-150		mV
Output Change at Yout	Self Test 0 to Self Test 1		+150		mV
OUTPUT AMPLIFIER					
Output Swing Low	No load		0.1		V
Output Swing High	No load		2.8		V
POWER SUPPLY					
Operating Voltage Range		1.8		5.25	v
Supply Current	$V_s = 3 V$		320		μΑ
Turn-On Time ⁷	No external filter		1		ms
TEMPERATURE					
Operating Temperature Range		-25		+70	°C

¹ Defined as coupling between two axes.

² Sensitivity is essentially ratiometric to Vs.

³ Defined as the output change from ambient-to-maximum temperature or ambient-to-minimum temperature.

⁴ Actual frequency response controlled by user-supplied external filter capacitors (Cx, Cy). ⁵ Bandwidth with external capacitors = $1/(2 \times \pi \times 32 \text{ k}\Omega \times \text{C})$. For Cx, Cy = 0.003 µF, bandwidth = 1.6 kHz. For Cx, Cy = 10 µF, bandwidth = 0.5 Hz.

 $^{\rm 6}$ Self-test response changes cubically with V_s.

⁷ Turn-on time is dependent on C_{x_r} , C_{Y} and is approximately $160 \times C_{x}$ or $C_{Y} + 1$ ms, where C_{x_r} , C_{Y} are in μ F.

ABSOLUTE MAXIMUM RATINGS

Table 2.

Parameter	Rating
Acceleration (Any Axis, Unpowered)	10,000 g
Acceleration (Any Axis, Powered)	10,000 g
Vs	–0.3 V to +7.0 V
All Other Pins	$(COM - 0.3 V)$ to $(V_{s} + 0.3 V)$
Output Short-Circuit Duration (Any Pin to Common)	Indefinite
Temperature Range (Powered)	–55°C to +125°C
Temperature Range (Storage)	–65°C to +150°C

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

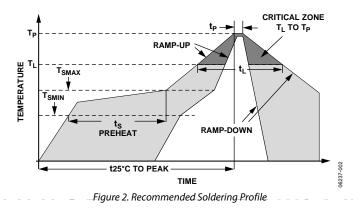


Table 3. Recommended Soldering Profile

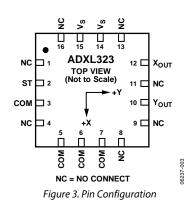
Profile Feature	Sn63/Pb37	Pb-Free	
Average Ramp Rate $(T_L \text{ to } T_P)$	3°C/sec max	3°C/sec max	
Preheat			
Minimum Temperature (T _{SMIN})	100°C	150°C	
Maximum Temperature (T _{SMAX})	150°C	200°C	
Time (T _{SMIN} to T _{SMAX}), ts	60 sec to 120 s	60 sec to 180 sec	
T _{SMAX} to T _L			
Ramp-Up Rate	3°C/sec max	3°C/sec max	
Time Maintained Above Liquidous (TL)			
Liquidous Temperature (TL)	183°C	217°C	
Time (t _L)	60 sec to 150 sec	60 sec to 150 sec	
Peak Temperature (T _P)	240°C + 0°C/–5°C	260°C + 0°C/-5°C	
Time within 5°C of Actual Peak Temperature (t _P)	10 sec to 30 sec	20 sec to 40 sec	
Ramp-Down Rate	6°C/sec max	6°C/sec max	
Time 25°C to Peak Temperature	6 minutes max	8 minutes max	

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



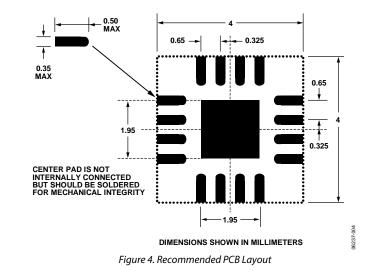
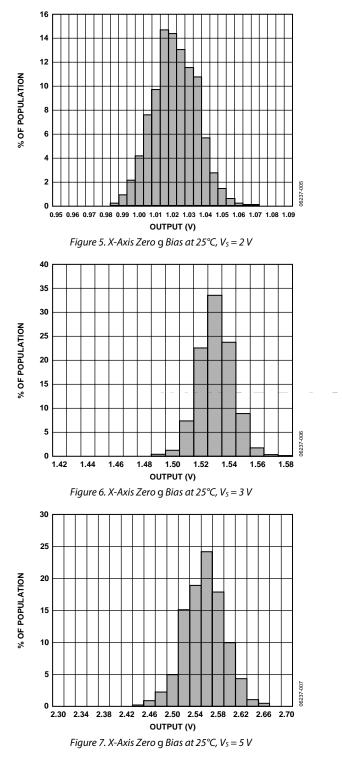


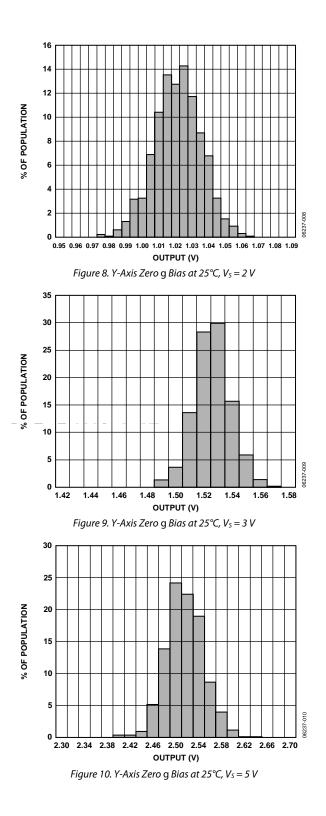
Table 4. Pin Function Descriptions

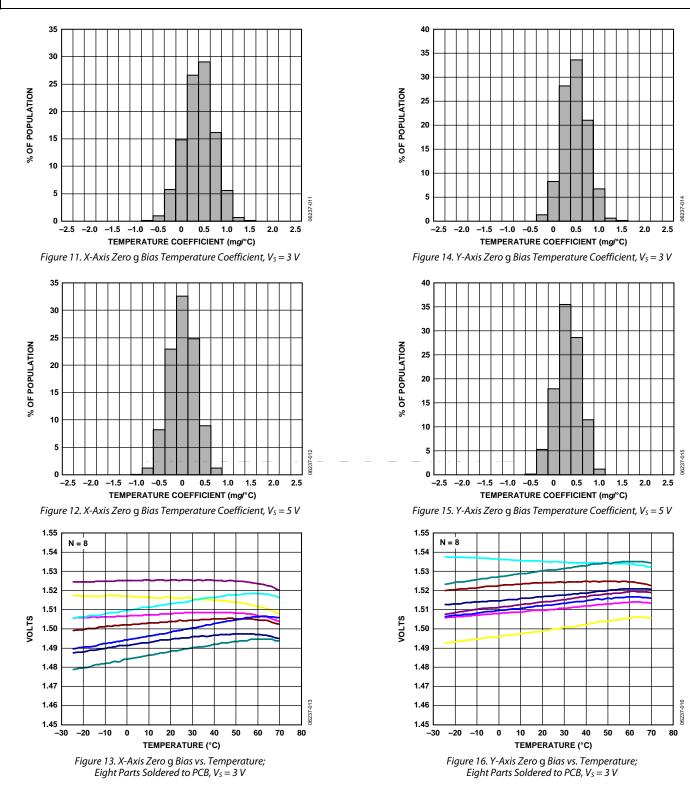
Pin No.	Mnemonic	Description
1	NC	No Connect
2	ST	SelfTest
3	COM	Common
4	NC	No Connect
5	СОМ	Common
6	COM	Common
7	COM	Common
8	NC	No Connect
9	NC	No Connect
10	Yout	Y Channel Output
11	NC	No Connect
12	Xout	X Channel Output
13	NC	No Connect
14	Vs	Supply Voltage (1.8 V to 5.25 V)
15	Vs	Supply Voltage (1.8 V to 5.25 V)
16	NC	No Connect

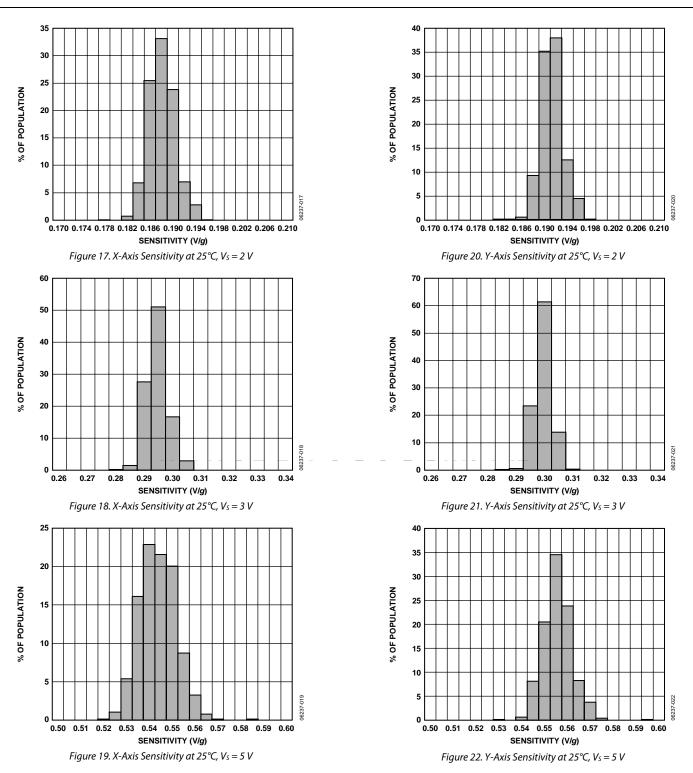
TYPICAL PERFORMANCE CHARACTERISTICS

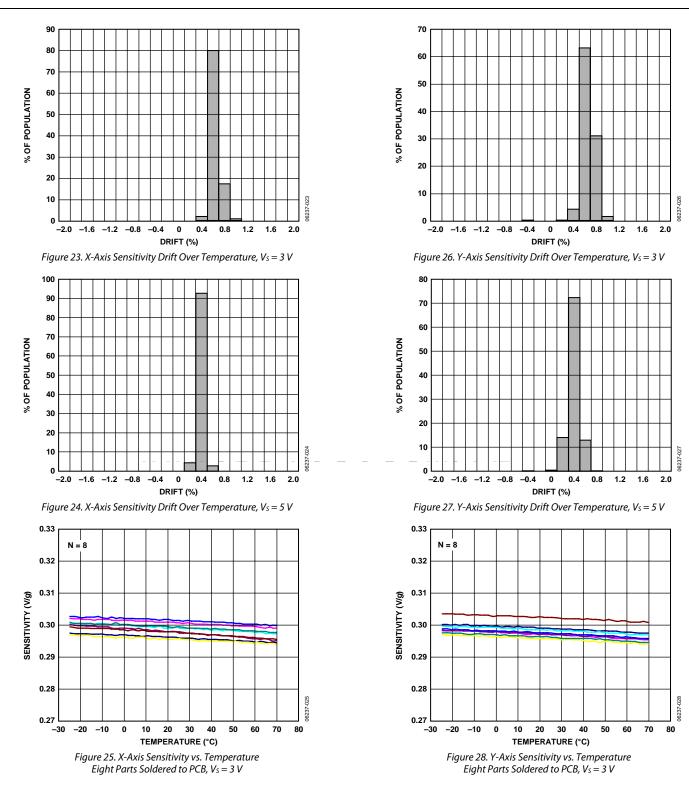
N > 1000 for all typical performance plots, unless otherwise noted.

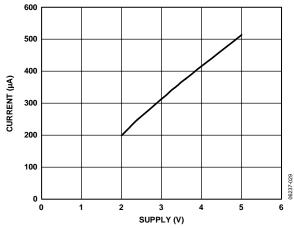


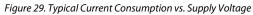


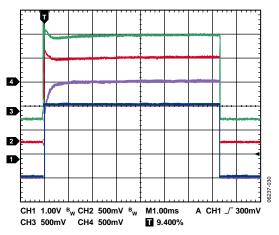














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THEORY OF OPERATION

The ADXL323 is a complete 2-axis acceleration measurement system on a single, monolithic IC. The ADXL323 has a measurement range of $\pm 3 g$ minimum. It contains a polysilicon surface micromachined sensor and signal conditioning circuitry to implement an open-loop acceleration measurement architecture. The output signals are analog voltages that are proportional to acceleration. The accelerometer can measure the static acceleration of gravity in tilt sensing applications, as well as dynamic acceleration resulting from motion, shock, or vibration.

The sensor is a polysilicon surface micromachined structure built on top of a silicon wafer. Polysilicon springs suspend the structure over the surface of the wafer and provide a resistance against acceleration forces. Deflection of the structure is measured using a differential capacitor that consists of independent fixed plates and plates attached to the moving mass. The fixed plates are driven by 180° out-of-phase square waves. Acceleration deflects the moving mass and unbalances the differential capacitor resulting in a sensor output whose amplitude is proportional to acceleration. Phase-sensitive demodulation techniques are then used to determine the magnitude and direction of the acceleration.

The demodulator output is amplified and brought off-chip through a 32 k Ω resistor. The user then sets the signal bandwidth of the device by adding a capacitor. This filtering improves measurement resolution and helps prevent aliasing.

MECHANICAL SENSOR

The ADXL323 uses a single structure for sensing the X-axis and Y-axis. As a result, the sense directions of the two axes are highly orthogonal with little cross axis sensitivity. Mechanical misalignment of the sensor die to the package is the chief source of cross axis sensitivity. Mechanical misalignment can, of course, be calibrated out at the system level.

PERFORMANCE

Rather than using additional temperature compensation circuitry, innovative design techniques ensure that high performance is built in to the ADXL323. As a result, there is neither quantization error nor nonmonotonic behavior, and temperature hysteresis is very low (typically less than 3 mg over the -25° C to $+70^{\circ}$ C temperature range).

Figure 13 and Figure 16 show the zero *g* output performance of eight parts (X-axis and Y-axis) soldered to a PCB over a -25° C to $+70^{\circ}$ C temperature range.

Figure 25 and Figure 28 demonstrate the typical sensitivity shift over temperature for supply voltages of 3 V. This is typically better than $\pm 1\%$ over the -25° C to $+70^{\circ}$ C temperature range.

APPLICATIONS POWER SUPPLY DECOUPLING

For most applications, a single 0.1 μ F capacitor, $C_{\rm DC}$, placed close to the ADXL323 supply pins adequately decouples the accelerometer from noise on the power supply. However, in applications where noise is present at the 50 kHz internal clock frequency (or any harmonic thereof), additional care in power supply bypassing is required because this noise can cause errors in acceleration measurement. If additional decoupling is needed, a 100 Ω (or smaller) resistor or ferrite bead can be inserted in the supply line. Additionally, a larger bulk bypass capacitor (1 μ F or greater) can be added in parallel to $C_{\rm DC}$. Ensure that the connection from the ADXL323 ground to the power supply ground is low impedance because noise transmitted through ground has an effect similar to that of noise transmitted through Vs.

SETTING THE BANDWIDTH USING C_x, C_y, AND C_z

The ADXL323 has provisions for band limiting the X_{OUT} pin and the Y_{OUT} pin. Capacitors must be added at these pins to implement low-pass filtering for antialiasing and noise reduction. The equation for the 3 dB bandwidth is

$$F_{-3 \text{ dB}} = 1/(2\pi(32 \text{ k}\Omega) \times C_{(X, Y, Z)})$$

or more simply

 $F_{-3 \text{ dB}} = 5 \ \mu \text{F} / C_{(X, Y, Z)}$

The tolerance of the internal resistor (R_{FILT}) typically varies as much as $\pm 15\%$ of its nominal value (32 k Ω), and the bandwidth varies accordingly. A minimum capacitance of 0.0047 μ F for C_x, C_y, and C_z is recommended in all cases.

Table 5. The Capacitor Selection, C _x , C _y , and C _z			
Bandwidth (Hz)	Capacitor (µF)		
1	4.7		
10	0.47		
50	0.10		
100	0.05		
200	0.027		
500	0.01		

SELF TEST

The ST pin controls the self-test feature. When this pin is set to Vs, an electrostatic force is exerted on the accelerometer beam. The resulting movement of the beam allows the user to test if the accelerometer is functional. The typical change in output is -500 mg (corresponding to -150 mV) in the X-axis, and 500 mg (or 150 mV) on the Y-axis. This ST pin can be left open circuit or connected to common (COM) in normal use.

Never expose the ST pin to voltages greater than $V_s + 0.3$ V. If this cannot be guaranteed due to the system design (for example, if there are multiple supply voltages), a low V_F clamping diode between ST and V_s is recommended.

DESIGN TRADE-OFFS FOR SELECTING FILTER CHARACTERISTICS: THE NOISE/BW TRADE-OFF

The selected accelerometer bandwidth ultimately determines the measurement resolution (smallest detectable acceleration). Filtering can be used to lower the noise floor to improve the resolution of the accelerometer. Resolution is dependent on the analog filter bandwidth at X_{OUT} and Y_{OUT} .

The output of the ADXL323 has a typical bandwidth of greater than 1600 Hz. The user must filter the signal at this point to limit aliasing errors. The analog bandwidth must be no more than half the analog-to-digital sampling frequency to minimize aliasing. The analog bandwidth can be further decreased to reduce noise and improve resolution.

The ADXL323 noise has the characteristics of white Gaussian noise, which contributes equally at all frequencies and is described in terms of $\mu g/\sqrt{Hz}$ (the noise is proportional to the square root of the accelerometer bandwidth). The user should limit bandwidth to the lowest frequency needed by the application to maximize the resolution and dynamic range of the accelerometer.

With the single-pole, roll-off characteristic, the typical noise of the ADXL323 is determined by

rms Noise = Noise Density $\times (\sqrt{BW \times 1.6})$

Often, the peak value of the noise is desired. Peak-to-peak noise can only be estimated by statistical methods. Table 6 is useful for estimating the probabilities of exceeding various peak values, given the rms value.

Table 6. I	Estimation	of Peak-to-	Peak Noise
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Peak-to-Peak Value	% of Time that Noise Exceeds Nominal Peak-to-Peak Value
2 × rms	32
4 × rms	4.6
6 × rms	0.27
8 × rms	0.006

USE WITH OPERATING VOLTAGES OTHER THAN 3 V

The ADXL323 is tested and specified at $V_s = 3 V$; however, it can be powered with V_s as low as 1.8 V or as high as 5.25 V. Note that some performance parameters change as the supply voltage is varied.

The ADXL323 output is ratiometric; therefore, the output sensitivity (or scale factor) varies proportionally to the supply voltage. At $V_s = 5$ V, the output sensitivity is typically 550 mV/g. At $V_s = 2$ V, the output sensitivity is typically 190 mV/g.

The zero *g* bias output is also ratiometric, so the zero *g* output is nominally equal to $V_s/2$ at all supply voltages.

The output noise is not ratiometric but is absolute in volts; therefore, the noise density decreases as the supply voltage increases. This is because the scale factor (mV/g) increases, while the noise voltage remains constant. At V_s = 5 V, the noise density is typically 180 $\mu g/\sqrt{Hz}$, while at V_s = 1.8 V, the noise density is typically 360 $\mu g/\sqrt{Hz}$.

Self-test response in *g* is roughly proportional to the square of the supply voltage. However, when ratiometricity of sensitivity is factored in with supply voltage, the self-test response in volts is roughly proportional to the cube of the supply voltage. For example, at $V_s = 5$ V, the self-test response for the ADXL323 is approximately –700 mV for the X-axis and +700 mV for the Y-axis.

At $V_s = 1.8$ V, the self-test response is approximately -40 mV for the X-axis and +40 mV for the Y-axis.

The supply current decreases as the supply voltage decreases. Typical current consumption at $V_s = 5$ V is 500 μ A, and typical current consumption at $V_s = 1.8$ V is 180 μ A.

AXES OF ACCELERATION SENSITIVITY

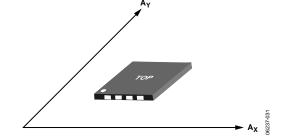


Figure 31. Axes of Acceleration Sensitivity, Corresponding Output Voltage Increases When Accelerated Along the Sensitive Axis

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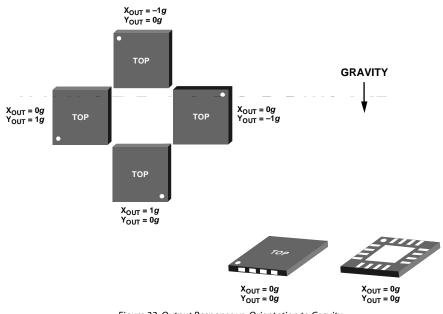
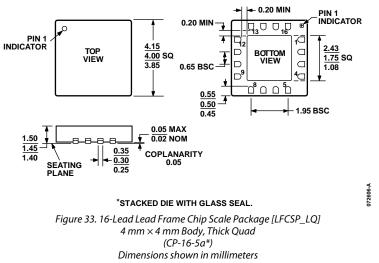


Figure 32. Output Response vs. Orientation to Gravity

OUTLINE DIMENSIONS



ORDERING GUIDE

Model	Measurement Range	Specified Voltage	Temperature Range	Package Description	Package Option
ADXL323KCPZ ¹	±3 g	3 V	-25°C to +70°C	16-Lead LFCSP_LQ	CP-16-5a
ADXL323KCPZ-RL ¹	±3 g	3 V	-25°C to +70°C	16-Lead LFCSP_LQ	CP-16-5a
EVAL-ADXL323Z ¹				Evaluation Board	

 1 Z = Pb-free part.

NOTES

Rev. 0 | Page 15 of 16

NOTES

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Rev. 0 | Page 16 of 16